

Search Notes

Application/Control No.

10/707,277

Examiner

Alan S. Chen

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2182

SEARCHED

Class	Subclass	Date	Examiner
710	8	5/2/2006	ASC
↓	20	↓	↓
↓	22	↓	↓
↓	62	↓	↓
↓	72	↓	↓
713	1	↓	↓
↓	2	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
see search history printouts			

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
(EAST) USPAT; USPGPUB; EPO; JPO; IBM_TDB; DERWENT PLUS; Inventor Search	5/2/2006	ASC
Tanh Nguyen	5/2/2006	ASC